## **Question Paper Code: 46404**

## B.E. / B.Tech. DEGREE EXAMINATION, NOV 2018

Sixth Semester

**Electronics and Communication Engineering** 

## 14UEC604-VLSI DESIGN

(Regulation 2014)

Duration: Three hours Maximum: 100 Marks

**Answer ALL Questions** 

(Smith chart may be permitted)

PART A -  $(10 \times 1 = 10 \text{ Marks})$ 

- VLSI technology uses \_\_\_\_\_\_ to form integrated circuit.
   (a) Transistors (b) Switches (c) Diodes (d) Buffers
- 2. The difficulty in achieving high doping concentration leads to
  - (a) Error in concentration

(b) Error in variation

(c) Error in doping

- (d) Distribution
- 3. In accordance to the scaling technology, the total delay of the logic circuit depends on
  - (a) The capacitor to be charged
  - (b) The voltage through which capacitance must be charged
  - (c) Available current
  - (d) All of the above

4.	The time needed for an output to change as the result of an input change is known as				
	(a) noise immunity (b) fanout	(c) propagation	n delay	(d) rise time	
5.	In CMOS circuits, which type of power dissipation occurs due to switching of transient current and charging and discharging of load capacitance?				
<ul><li>(a) Static dissipation</li><li>(c) Both (a) and (b)</li></ul>		<ul><li>(b) Dynamic dissipation</li><li>(d) None of these</li></ul>			
6. 7	The sequential circuit is also called				
	(a) Flip-flop (b) Latch	(c) Strobe	(d) Nor	ne of the Mentioned	
7.	Boundary scan test is used to test				
	(a) Pins (b) Multip	liers (c) Boards	ı	(d) wires	
8.	CMOS domino logic occupies				
	(a) Smaller area	(b) Larger area			
9.	(c) Both of the mentioned  Test Benches procedure is		(d) None of the mentioned		
	(a) Smaller design	(b) Larger desig	(b) Larger design		
10.	(c) Complicated Blocking & Non blocking assignment	(d) None of the r	mentione	ed	
	<ul><li>(a) =statement &amp; ≤ statement</li><li>(c) Statement</li></ul>	(b) ≤ statement $(d) ≥ statement$		ement	
	PART -	B $(5 \times 2 = 10 \text{ Marks})$			
11.	. What is Body effect and channel Length modulation?				
12.	2. Define design margin.				
13.	Draw the pseudo nmos inverter.				
14.	. What is stuck – at fault?				
15.	What is the structural gate-level mod	deling?			
	PART - C	$C (5 \times 16 = 80 \text{ Marks})$			

16. (a) Explain layout design rules in detail.	(16)
Or	
(b) (i) Explain the DC transfer characteristics of CMOS inverter conditions for the different regions.	with necessary (8)
(ii) Obtain the threshold voltage equation for different threshold	voltage effects. (8)
17.(a) Explain the concept of delay estimation, logical effort and sizing of M	
Or	
(b) Explain the static and dynamic power dissipation in CMOS circuits w diagrams and expressions.	vith necessary (16)
18. (a) Explain in detail: (i) Conventional CMOS Latch (ii) Conventional C	CMOS Flip flop. (16)
Or	
(b) Explain in detail about sequencing dynamic circuits and synchronize	rs. (16)
19. (a) Explain system level test techniques/boundary scan test.	(16)
Or	
(b) (i) Explain Ad-Hoc testing and Built in soft test techniques.	(8)
(ii) What are the challenges involved in silicon debugging? Explain.	(8)
20. (a) Explain the concept involved in structural gate level modeling and description for Decoder and parity encoder.	nd also give the
Or	
(b) Write the verilog code in gate level modeling for multiplexer and D-l	latch. (16)